Freescale Semiconductor - MPC8535BVTANGA Datasheet

Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	800MHz
Co-Processors/DSP	-
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	SATA 3Gbps (1)
USB	USB 2.0 (2)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8535bvtanga

	A	B	C	D	E	F	G	H	J	K	L	M	N	P
1		GV_{DD}	$\overline{\text{MDQS}}$ [5]	MDQ [32]	MDQ [46]	MDQ [47]	MDQ [34]	GND	MDQ [56]	MDQ [57]	GND	GV_{DD}	MDQS [7]	MDQ [58]
2	MDQ [44]	MDQ [40]	MDM [5]	MDQS [5]	GV_{DD}	MDQ [42]	MDQ [43]	MDQ [35]	MDQ [60]	MDQ [61]	MDM [7]	$\overline{\text{MDQS}}$ [7]	GND	MDM [62]
3	GND	MDQ [45]	MDQ [41]	$\overline{\text{MCS}}$ [0]	GND	MDQ [33]	GV_{DD}	MDQ [38]	MDQ [52]	GV_{DD}	MDM [6]	MDQS [6]	MDQ [50]	MDQ [51]
4	MBA [0]	$\overline{\text{MWE}}$	$\overline{\text{MCS}}$ [2]	GV_{DD}	MDQ [36]	GND	MDM [4]	GND	MDQ [39]	MDQ [53]	MDQ [49]	$\overline{\text{MDQS}}$ [6]	MDQ [54]	MDQ [55]
5	MA [10]	MBA [1]	$\overline{\text{MRAS}}$	GND	MODT [0]	GV_{DD}	MDQ [37]	GV_{DD}	$\overline{\text{MDQS}}$ [4]	MDQS [4]	MDQ [48]	GND	GV_{DD}	GND
6	MAPAR_OUT	NC	GND	GV_{DD}	MODT [2]	MODT [3]	$\overline{\text{MCS}}$ [3]	$\overline{\text{MCS}}$ [1]	MCK [2]	$\overline{\text{MCK}}$ [2]	SD2_IMP_CAL_TX	SD2_REF_CLK	S2GND	SD2_RX [0]
7	GND	MA [0]	GV_{DD}	NC	$\overline{\text{MCAS}}$	MA [13]	GV_{DD}	MODT [1]	NC	GND	SD2_PLL_TPD	$\overline{\text{SD2\_REF\_CLK}}$	$S2V_{DD}$	$\overline{\text{SD2\_RX}}$ [0]
8	MCK [3]	$\overline{\text{MCK}}$ [3]	MA [2]	GND	GV_{DD}	GND	MA [1]	MCK [5]	$\overline{\text{MCK}}$ [5]	GND	Rsvd	S2GND	SD2_RX [1]	S2GND
9	MCK [0]	$\overline{\text{MCK}}$ [0]	GV_{DD}	MA [4]	MA [8]	MA [7]	GV_{DD}	MCKE [3]	NC	NC	Rsvd	$S2V_{DD}$	$\overline{\text{SD2\_RX}}$ [1]	S2GND
10	MA [3]	GND	MA [5]	NC	MA [14]	MA [15]	MCKE [2]	MCKE [0]	GV_{DD}	MCKE [1]	NC	X2GND	NC	NC
11	MA [6]	GV_{DD}	MECC [3]	MA [12]	GV_{DD}	MECC [2]	GV_{DD}	$\overline{\text{MCK}}$ [1]	MCK [1]	GND	$X2V_{DD}$	SD2_TX [1]	X2GND	SD2_TX [0]
12	MA [11]	MA [9]	GND	MECC [7]	GND	NC	MECC [0]	GV_{DD}	GND	GV_{DD}	X2GND	$\overline{\text{SD2\_TX}}$ [1]	$X2V_{DD}$	$\overline{\text{SD2\_TX}}$ [0]
13	$\overline{\text{MAPAR\_ERR}}$	MBA [2]	MECC [6]	MDQS [8]	$\overline{\text{MDQS}}$ [8]	MDM [8]	GND	$\overline{\text{MCK}}$ [4]	MCK [4]	VDD_CORE	GND	VDD_CORE	GND	VDD_CORE
14	GND	MDQ [27]	GV_{DD}	MECC [1]	GV_{DD}	MECC [5]	MECC [4]	GV_{DD}	GND	GV_{DD}	VDD_CORE	GND	VDD_CORE	GND

DETAIL A

Figure 3. Chip Pin Map Detail A

DETAIL C

	A	B	C	D	E	F	G	H	J	K	L	M	N	P
15	MDQ [26]	MDQ [31]	GND	GV_{DD}	GND	GV_{DD}	GND	MDIC [0]	GND	MDIC [1]	GND	VDD_ CORE	GND	VDD_ CORE
16	MDQ [30]	MDQS [3]	MDQ [19]	MDQ [23]	MDQ [18]	GND	LCS [4]	LCS5/ DMA_ DREQ2	LCS6/ DMA_ DACK2	LA [28]	VDD_ CORE	GND	VDD_ CORE	GND
17	MDQS [3]	MDM [3]	GV_{DD}	GND	MDQS [2]	MDQ [22]	LA [31]	LA [30]	GND	LA [29]	GND	VDD_ PLAT	GND	VDD_ PLAT
18	MDQ [25]	MDQ [24]	MDQS [2]	MDM [2]	GV_{DD}	MDQ [21]	GND	LGPL3/ LFWP	BV_{DD}	LCS [0]	LCS7/ DMA_ DDONE2	GND	VDD_ PLAT	GND
19	MDQ [29]	MDQ [28]	NC	MDQ [17]	MDQ [16]	MDQ [20]	LCS [1]	LCS [2]	BV_{DD}	LGPL5	LA [27]	VDD_ PLAT	GND	VDD_ PLAT
20	MDQ [11]	MDQ [10]	GND	GV_{DD}	GND	BV_{DD}	LGPL2/ LOE/ LFRE	LCS [3]	LGPL0/ LFCLE	LGPL1/ LFALE	LGPL4/ LGTA/ LUPWAIT/ LPBSE/ LFRB	XGND	SD1_TX [1]	XV_{DD}
21	MDQ [15]	MDQ [14]	GV_{DD}	MDQ [3]	MDQ [7]	GND	LAD [31]	LWE[3]/ LBS[3]	BV_{DD}	GND	LAD [1]	XV_{DD}	SD1_TX [1]	XGND
22	MDQS [1]	MDQS [1]	MDQ [2]	MDQ [6]	GV_{DD}	LAD [29]	LAD [30]	LWE[1]/ LBS[1]	LWE0/ LBS0/ LFWE	LAD [0]	LAD [2]	SD1_TX [0]	XGND	SD1_TX [2]
23	MDQ [9]	MDM [1]	MDQS [0]	GND	LAD [27]	BV_{DD}	LAD [28]	LWE[2]/ LBS[2]	BV_{DD}	LAD [3]	BV_{DD}	SD1_TX [0]	XV_{DD}	SD1_TX [2]
24	MDQ [8]	MDQ [13]	GV_{DD}	MDQS [0]	LAD [24]	LAD [23]	LAD [26]	LCLK [0]	LCLK [1]	LAD [4]	LAD [5]	XGND	NC	SGND
25	MDQ [12]	MDQ [5]	MDM [0]	MDQ [4]	LDP [3]	LAD [19]	GND	LCLK [2]	LBCTL	LAD [7]	LAD [6]	NC	SV_{DD}	SD1_RX [1]
26	MDQ [0]	MDQ [1]	LAD [25]	GND	LAD [22]	LAD [18]	LAD [16]	BV_{DD}	LALE	LDP [0]	GND	SD1_ IMP_CAL _RX	SGND	SD1_RX [1]
27	GND	LDP [2]	GND	LSYNC_ IN	LAD [21]	GND	LAD [15]	LAD [14]	GND	LAD [11]	LAD [9]	SV_{DD}	SD1_RX [0]	SGND
28	MVREF	GND	AVDD_ LBIU	LSYNC_ OUT	LAD [20]	LAD [17]	LDP [1]	LAD [13]	LAD [12]	LAD [10]	LAD [8]	SGND	SD1_RX [0]	SV_{DD}

Figure 5. Chip Pin Map Detail C

Table 1. Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
TSEC3_TX_CLK	Transmit clock In	U10	I	TV_{DD}	—
TSEC3_GTX_CLK	Transmit clock Out	U5	O	TV_{DD}	—
TSEC3_CRS	Carrier sense	T10	I/O	TV_{DD}	17
TSEC3_COL	Collision detect	T9	I	TV_{DD}	—
TSEC3_RXD[7:0]	Receive data	U12,U13,U6,V6,V1,U3, U2,V3	I	TV_{DD}	—
TSEC3_RX_DV	Receive data valid	V2	I	TV_{DD}	—
TSEC3_RX_ER	Receive data error	T4	I	TV_{DD}	—
TSEC3_RX_CLK	Receive clock	U1	I	TV_{DD}	—
IEEE 1588					
TSEC_1588_CLK	Clock In	W9	I	LV_{DD}	29
TSEC_1588_TRIG_IN[0:1]	Trigger In	W8,W7	I	LV_{DD}	29
TSEC_1588_TRIG_OUT[0:1]	Trigger Out	U11,W10	O	LV_{DD}	5,9,29
TSEC_1588_CLK_OUT	Clock Out	V10	O	LV_{DD}	5,9,29
TSEC_1588_PULSE_OUT1	Pulse Out1	V11	O	LV_{DD}	5,9,29
TSEC_1588_PULSE_OUT2	Pulse Out2	T11	O	LV_{DD}	5,9,29
eSDHC					
SDHC_CMD	Command line	AH10	I/O	OV_{DD}	29
$\overline{\text{SDHC\_CD}}$/GPIO[4]	Card detection	AH11	I	OV_{DD}	—
SDHC_DAT[0:3]	Data line	AG12,AH12,AH13, AG11	I/O	OV_{DD}	29
SDHC_DAT[4:7] / SPI_CS[0:3]	8-bit MMC Data line / SPI chip select	AE8,AC10,AF9,AA10	I/O	OV_{DD}	29
SDHC_CLK	SD/MMC/SDIO clock	AG13	I/O	OV_{DD}	29
$\overline{\text{SDHC\_WP}}$/GPIO[5]	Card write protection	AG10	I	OV_{DD}	1, 32
eSPI					
SPI_MOSI	Master Out Slave In	AF8	I/O	OV_{DD}	29
SPI_MISO	Master In Slave Out	AD9	I	OV_{DD}	29
SPI_CLK	eSPI clock	AD8	I/O	OV_{DD}	29
SPI_CS[0:3] / SDHC_DAT[4:7]	eSPI chip select / SDHC 8-bit MMC data	AE8,AC10,AF9,AA10	I/O	OV_{DD}	29
DUART					
$\overline{\text{UART\_CTS}}$[0:1]	Clear to send	AE11,Y12	I	OV_{DD}	29
$\overline{\text{UART\_RTS}}$[0:1]	Ready to send	AB12,AD12	O	OV_{DD}	29
UART_SIN[0:1]	Receive data	AC12,AF12	I	OV_{DD}	29

Table 1. Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes

Notes:

1. All multiplexed signals may be listed only once and may not re-occur.
2. Recommend a weak pull-up resistor (2–10 KΩ) be placed on this pin to OV_{DD}.
3. This pin must always be pulled-high.
4. This pin is an open drain signal.
5. This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pullup or active driver is needed.
6. Treat these pins as no connects (NC) unless using debug address functionality.
7. The value of LA[28:31] during reset sets the CCB clock to SYSCLK PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See Section 22.2, “CCB/SYSCLK PLL Ratio.”
8. The value of LALE, LGPL2 and LBCTL at reset set the e500 core clock to CCB Clock PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See the Section 22.3, “e500 Core PLL Ratio.”
9. Functionally, this pin is an output, but structurally it is an I/O because it either samples configuration input during reset or because it has other manufacturing test functions. This pin will therefore be described as an I/O for boundary scan.
10. For proper state of these signals during reset, UART_SOUT[1] must be pulled down to GND through a resistor. UART_SOUT[0] can be pulled up or left without a resistor. However, if there is any device on the net which might pull down the value of the net at reset, then a pullup is needed on UART_SOUT[0].
11. This output is actively driven during reset rather than being three-stated during reset.
12. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
13. These pins are connected to the V_{DD_CORE}/V_{DD_PLAT}/GND planes internally and may be used by the core power supply to improve tracking and regulation.
15. These pins have other manufacturing or debug test functions. It’s recommended to add both pull-up resistor pads to OVDD and pull-down resistor pads to GND on board to support future debug testing when needed.
16. If this pin is connected to a device that pulls down during reset, an external pull-up is required to drive this pin to a safe state during reset.
17. This pin is only an output in FIFO mode when used as Rx Flow Control.
18. Do not connect.
19. These must be pulled up (100 Ω- 1 kΩ) to OVDD.
20. Independent supplies derived from board VDD.
21. Recommend a pull-up resistor (1 KΩ) be placed on this pin to OV_{DD}.
22. The following pins must NOT be pulled down during power-on reset: MDVAL, UART_SOUT[0], EC_MDC, TSEC1_TXD[3], TSEC3_TXD[7], HRESET_REQ, TRIG_OUT/READY/$\overline{\text{QUIESCE}}$, MSRCID[2:4], ASLEEP.
23. This pin requires an external 4.7-kΩ pull-down resistor to prevent PHY from seeing a valid Transmit Enable before it is actively driven.
24. General-Purpose POR configuration of user system.

Table 19. DDR SDRAM Output AC Timing Specifications (continued)

At recommended operating conditions with GV_{DD} of 1.8 V ± 5% for DDR2 or 1.5 V ± 5% for DDR3.

Parameter	Symbol [1]	Min	Max	Unit	Notes
<= 667 MHz		$0.9 \times t_{MCK}$			7
MDQS epilogue end	t_{DDKHME}			ns	6
<= 667 MHz		$0.4 \times t_{MCK}$	$0.6 \times t_{MCK}$		7

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
2. All MCK/$\overline{\text{MCK}}$ referenced measurements are made from the crossing of the two signals ±0.1 V.
3. ADDR/CMD includes all DDR SDRAM output signals except MCK/$\overline{\text{MCK}}$, $\overline{\text{MCS}}$, and MDQ/MECC/MDM/MDQS.
4. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK[n] clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. This will typically be set to the same delay as the clock adjust in the CLK_CNTL register. The timing parameters listed in the table assume that these 2 parameters have been set to the same adjustment value. See the *MPC8536E PowerQUICC III Integrated Processor Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.
5. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the microprocessor.
6. All outputs are referenced to the rising edge of MCK[n] at the pins of the microprocessor. Note that t_{DDKHMP} follows the symbol conventions described in note 1.
7. Maximum DDR2 and DDR3 frequency is 667 MHz

NOTE

For the ADDR/CMD setup and hold specifications in Table 19, it is assumed that the Clock Control register is set to adjust the memory clocks by 1/2 applied cycle.

This figure provides the AC test load for the DDR bus.

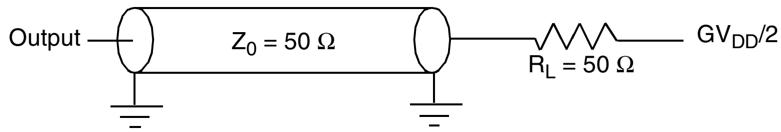

Figure 11. DDR AC Test Load

2.7 eSPI

This section describes the DC and AC electrical specifications for the eSPI of the chip.

2.7.1 eSPI DC Electrical Characteristics

This table provides the DC electrical characteristics for the chip eSPI.

Table 20. SPI DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –6.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 6.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	0 V ≤ V_{IN} ≤ OV_{DD}	—	±10	μA

2.7.2 eSPI AC Timing Specifications

This table and provide the eSPI input and output AC timing specifications.

Table 21. SPI AC Timing Specifications[1]

Characteristic	Symbol [2]	Min	Max	Unit	Note
SPI_MOSI output—Master data hold time	t_{NIKHOX}	0.5	—	ns	3
	t_{NIKHOX}	4.0			4
SPI_MOSI output—Master data delay	t_{NIKHOV}	—	6.0	ns	3
	t_{NIKHOV}		7.4		4
SPI_CS outputs—Master data hold time	$t_{NIKHOX2}$	0	—	ns	—

This figures provide the AC test load and signals for the USB, respectively.

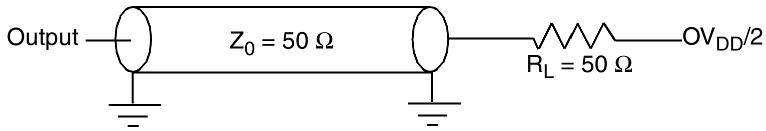

Figure 36. USB AC Test Load

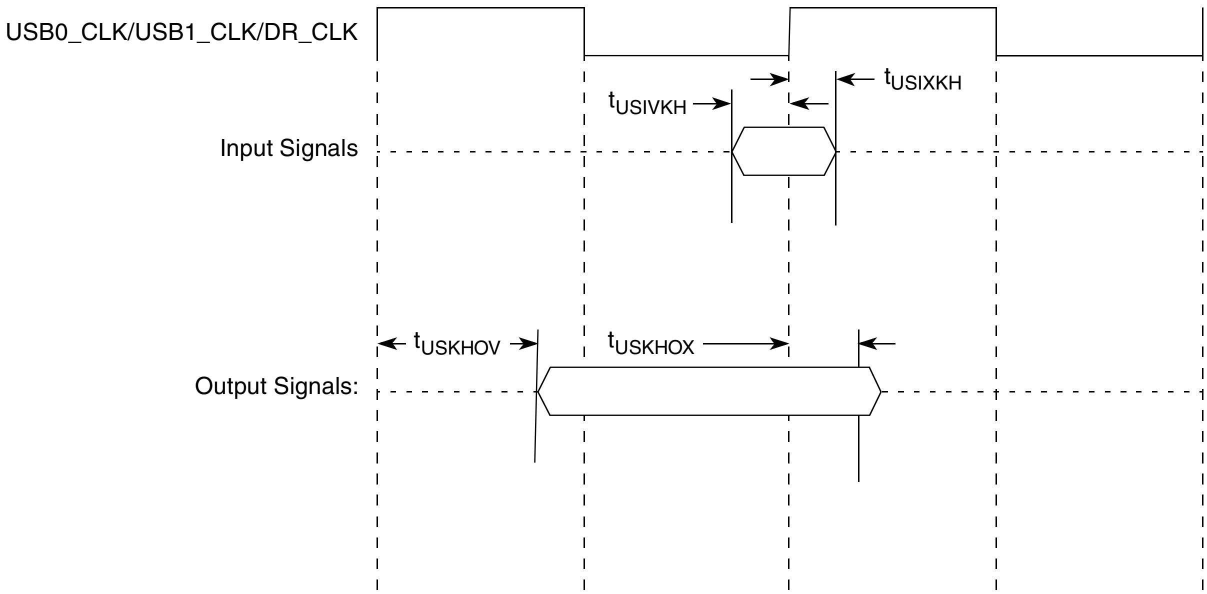

Figure 37. USB Signals

This table provides the DC electrical characteristics for the local bus interface operating at BV_{DD} = 1.8 V DC.

Table 50. Local Bus DC Electrical Characteristics (1.8 V DC)

Parameter	Symbol	Condition	Min	Max	Unit
Supply voltage 1.8V	BV_{DD}	—	1.71	1.89	V
High-level input voltage	V_{IH}	—	$0.65*BV_{DD}$	$0.3+BV_{DD}$	V
Low-level input voltage	V_{IL}	—	–0.3	$0.35*BV_{DD}$	V
Input current (BV_{IN} [1] = 0 V or $BV_{IN} = BV_{DD}$)	I_{IN}	—	-15	10	µA
High-level output voltage	V_{OH}	I_{OH} = –100 µA	BV_{DD} – 0.2	—	V
		I_{OH} = –2 mA	BV_{DD} – 0.45	—	
Low-level output voltage	V_{OL}	I_{OH} = 100 µA	—	0.2	V
		I_{OH} = 2 mA	—	0.45	

Note:

1. Note that the symbol BV_{IN}, in this case, represents the BV_{IN} symbol referenced in Table 1.

2.12.2 Local Bus AC Electrical Specifications

This table describes the general timing parameters of the local bus interface at BV_{DD} = 3.3 V DC. For information about the frequency range of local bus see Section 2.23.1, "Clock Ranges."

Table 51. Local Bus General Timing Parameters (BV_{DD} = 3.3 V DC)

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	7.5	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	tLBKSKEW		150	ps	7
Input setup to local bus clock (except LUPWAIT)	$t_{LBIVKH1}$	1.8	—	ns	3, 4
LUPWAIT input setup to local bus clock	$t_{LBIVKH2}$	1.7	—	ns	3, 4
Input hold from local bus clock (except LUPWAIT)	$t_{LBIXKH1}$	1.0	—	ns	3, 4
LUPWAIT input hold from local bus clock	$t_{LBIXKH2}$	1.0	—	ns	3, 4
LALE output transition to LAD/LDP output transition (LATCH setup and hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.3	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.4	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.3	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.3	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.7	—	ns	3

Table 61. Differential Receiver (RX) Input Characteristics (continued)

Parameter	Symbol	Min	Typical	Max	Units	Notes
RX Differential Mode Return loss 150 MHz - 300 MHz 300 MHz - 600 MHz 600 MHz - 1.2 GHz 1.2 GHz - 2.4 GHz 2.4 GHz - 3.0 GHz 3.0 GHz - 5.0 GHz	RL_{SATA_RXDD11}	— — — — — —	— — — — — —	18 14 10 8 3 1	dB	2, 3
RX Common Mode Return loss 150 MHz - 300 MHz 300 MHz - 600 MHz 600 MHz - 1.2 GHz 1.2 GHz - 2.4 GHz 2.4 GHz - 3.0 GHz 3.0 GHz - 5.0 GHz	RL_{SATA_RXCC11}	— — — — — —	— — — — — —	5 5 2 2 2 1	dB	2, 3, 4
RX Impedance Balance 150 MHz - 300 MHz 300 MHz - 600 MHz 600 MHz - 1.2 GHz 1.2 GHz - 2.4 GHz 2.4 GHz - 3.0 GHz 3.0 GHz - 5.0 GHz	RL_{SATA_RXDC11}	— — — — — —	— — — — — —	30 30 20 10 4 4	dB	2, 3
Deterministic jitter 1.5G 3.0G	U_{SATA_RXDJ}	—	—	0.4 0.47	UI	—
Total Jitter 1.5G 3.0G	U_{SATA_RXTJ}	—	—	0.65 0.65	UI	—

Notes:
1. The min values apply only to Gen1m, and Gen2m. the min values for Gen1i is 325 mVp-p and for Gen2i is 275 mVp-p.
2. Only applies when operating in 3.0Gb data rate mode.
3. The max value stated for 3.0 GHz - 5.0 GHz range only applies to Gen2i mode and not to Gen2m mode.
4. The max value stated for 2.4 GHz - 3.0 GHz range only applies to Gen2i mode for Gen2m the value is 1.
5. Only applies to Gen1i mode.

2.19 PCI

This section describes the DC and AC electrical specifications for the PCI bus of the chip.

2.19.1 PCI DC Electrical Characteristics

This table provides the DC electrical characteristics for the PCI interface.

Table 67. PCI DC Electrical Characteristics [1]

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	OV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.8	V
Input current (V_{IN} [2] = 0 V or V_{IN} = V_{DD})	I_{IN}	—	±5	μA
High-level output voltage (OV_{DD} = min, I_{OH} = –2 mA)	V_{OH}	2.4	—	V
Low-level output voltage (OV_{DD} = min, I_{OL} = 2 mA)	V_{OL}	—	0.4	V

Notes:

1. Ranges listed do not meet the full range of the DC specifications of the *PCI 2.2 Local Bus Specifications*.
2. The symbol V_{IN}, in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

2.19.2 PCI AC Electrical Specifications

This section describes the general AC timing parameters of the PCI bus. Note that the SYSCLK signal is used as the PCI input clock. This table provides the PCI AC timing specifications at 66 MHz.

Table 68. PCI AC Timing Specifications at 66 MHz

Parameter	Symbol [1]	Min	Max	Unit	Notes
SYSCLK to output valid	t_{PCKHOV}	—	6.0	ns	2, 3
Output hold from SYSCLK	t_{PCKHOX}	2.0	—	ns	2
SYSCLK to output high impedance	t_{PCKHOZ}	—	14	ns	2, 4
Input setup to SYSCLK	t_{PCIVKH}	3.0	—	ns	2, 5
Input hold from SYSCLK	t_{PCIXKH}	0	—	ns	2, 5
$\overline{REQ64}$ to $\overline{HRESET}$ [9] setup time	t_{PCRVRH}	$10 \times t_{SYS}$	—	clocks	6, 7
$\overline{HRESET}$ to $\overline{REQ64}$ hold time	t_{PCRHRX}	0	50	ns	7

Table 68. PCI AC Timing Specifications at 66 MHz (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
$\overline{\text{HRESET}}$ high to first $\overline{\text{FRAME}}$ assertion	t_{PCRHFV}	10	—	clocks	8
Rise time (20%–80%)	t_{PCICLK}	0.6	2.1	ns	—
Failing time (20%–80%)	t_{PCICLK}	0.6	2.1	ns	—

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the SYSCLK clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
2. See the timing measurement conditions in the *PCI 2.2 Local Bus Specifications*.
3. All PCI signals are measured from $OV_{DD}/2$ of the rising edge of PCI_SYNC_IN to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V PCI signaling levels.
4. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
5. Input timings are measured at the pin.
6. The timing parameter t_{SYS} indicates the minimum and maximum CLK cycle times for the various specified frequencies. The system clock period must be kept within the minimum and maximum defined ranges. For values see Section 22, "Clocking."
7. The setup and hold time is with respect to the rising edge of $\overline{\text{HRESET}}$.
8. The timing parameter t_{PCRHFV} is a minimum of 10 clocks rather than the minimum of 5 clocks in the *PCI 2.2 Local Bus Specifications*.
9. The reset assertion timing requirement for $\overline{\text{HRESET}}$ is 100 μs.

This figure provides the AC test load for PCI.

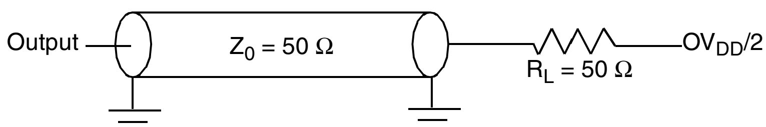

Figure 54. PCI AC Test Load

This figure shows the PCI input AC timing conditions.

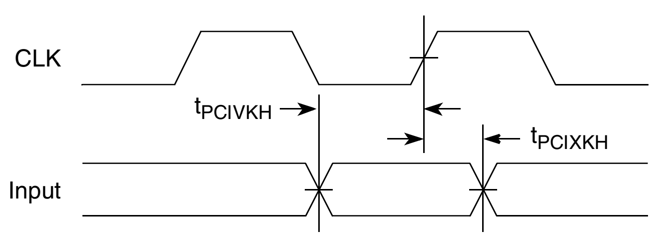

Figure 55. PCI Input AC Timing Measurement Conditions

This figure shows the PCI output AC timing conditions.

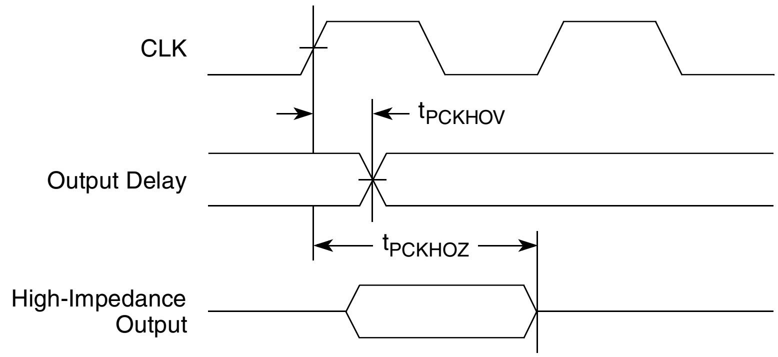

Figure 56. PCI Output AC Timing Measurement Condition

2.20 High-Speed Serial Interfaces

This chip features two Serializer/Deserializer (SerDes) interfaces to be used for high-speed serial interconnect applications. The SerDes1 interface is dedicated for PCI Express data transfers. The SerDes2 can be used for SGMII or SATA.

This section describes the common portion of SerDes DC electrical specifications, which is the DC requirement for SerDes Reference Clocks. The SerDes data lane's transmitter and receiver reference circuits are also shown.

2.20.1 Signal Terms Definition

The SerDes utilizes differential signaling to transfer data across the serial link. This section defines terms used in the description and specification of differential signals.

Figure 57 shows how the signals are defined. For illustration purposes, only one SerDes lane is used for description. The figure shows waveform for either a transmitter output (SDn_TX and $\overline{\text{SDn\_TX}}$) or a receiver input (SDn_RX and $\overline{\text{SDn\_RX}}$). Each signal swings between A Volts and B Volts where A > B.

Using this waveform, the definitions are as follows. To simplify illustration, the following definitions assume that the SerDes transmitter and receiver operate in a fully symmetrical differential signaling environment.

1. **Single-Ended Swing**

The transmitter output signals and the receiver input signals SDn_TX, $\overline{\text{SDn\_TX}}$, SDn_RX and $\overline{\text{SDn\_RX}}$ each have a peak-to-peak swing of A - B Volts. This is also referred as each signal wire's Single-Ended Swing.

2. **Differential Output Voltage, V_{OD}** (or **Differential Output Swing**):

The Differential Output Voltage (or Swing) of the transmitter, V_{OD}, is defined as the difference of the two complimentary output voltages: $V_{SDn\_TX} - V_{\overline{SDn\_TX}}$. The V_{OD} value can be either positive or negative.

3. **Differential Input Voltage, V_{ID}** (or **Differential Input Swing**):

The Differential Input Voltage (or Swing) of the receiver, V_{ID}, is defined as the difference of the two complimentary input voltages: $V_{SDn\_RX} - V_{\overline{SDn\_RX}}$. The V_{ID} value can be either positive or negative.

4. **Differential Peak Voltage**, V_{DIFFp}

The peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak Voltage, $V_{DIFFp} = |A - B|$ Volts.

5. **Differential Peak-to-Peak**, $V_{DIFFp-p}$

Since the differential output signal of the transmitter and the differential input signal of the receiver each range from A - B to -(A - B) Volts, the peak-to-peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak-to-Peak Voltage, $V_{DIFFp-p} = 2{*}V_{DIFFp} = 2 * |(A - B)|$ Volts, which is twice of differential swing in amplitude, or twice of the differential peak. For example, the output differential peak-peak voltage can also be calculated as $V_{TX\text{-}DIFFp\text{-}p} = 2*|V_{OD}|$.

6. **Common Mode Voltage, V_{cm}**

The Common Mode Voltage is equal to one half of the sum of the voltages between each conductor of a balanced interchange circuit and ground. In this example, for SerDes output, $V_{cm\_out} = V_{SDn\_TX} + V_{\overline{SDn\_TX}} = (A + B) / 2$, which is the arithmetic mean of the two complimentary output voltages within a differential pair. In a system, the common mode voltage may often differ from one component's output to the other's input. Sometimes, it may be even different between the receiver input and driver output circuits within the same component. It is also referred as the DC offset in some occasion.

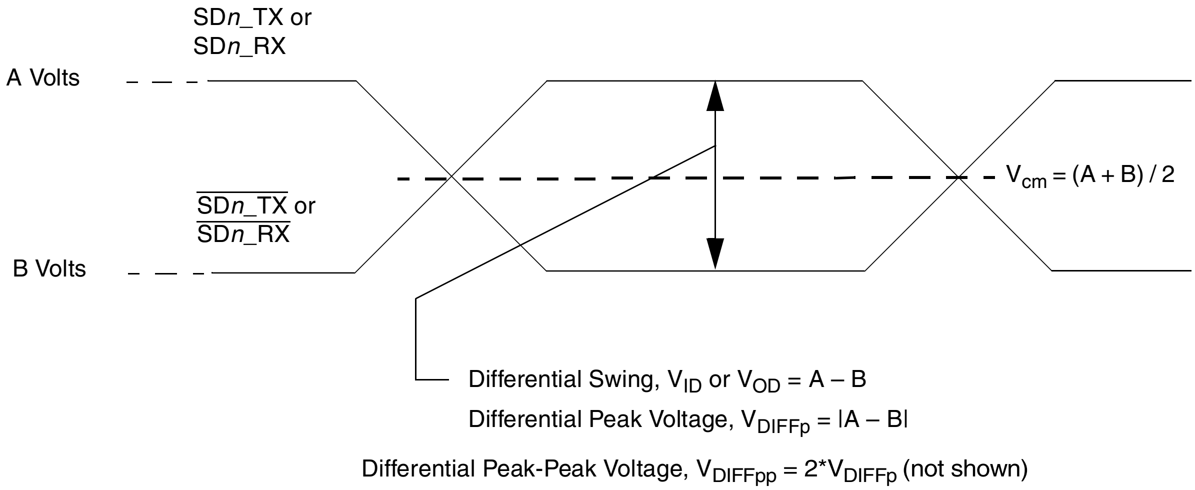

Figure 57. Differential Voltage Definitions for Transmitter or Receiver

To illustrate these definitions using real values, consider the case of a CML (Current Mode Logic) transmitter that has a common mode voltage of 2.25 V and each of its outputs, TD and $\overline{\text{TD}}$, has a swing that goes between 2.5V and 2.0V. Using these values, the peak-to-peak voltage swing of each signal (TD or $\overline{\text{TD}}$) is 500 mV p-p, which is referred as the single-ended swing for each signal. In this example, since the differential signaling environment is fully symmetrical, the transmitter output's differential swing (V_{OD}) has the same amplitude as each signal's single-ended swing. The differential output signal ranges between 500 mV and –500 mV, in other words, V_{OD} is 500 mV in one phase and –500 mV in the other phase. The peak differential voltage (V_{DIFFp}) is 500 mV. The peak-to-peak differential voltage ($V_{DIFFp\text{-}p}$) is 1000 mV p-p.

2.20.2 SerDes Reference Clocks

The SerDes reference clock inputs are applied to an internal PLL whose output creates the clock used by the corresponding SerDes lanes. The SerDes reference clocks for PCI Express are SD1_REF_CLK and, $\overline{\text{SD1\_REF\_CLK}}$. The SerDes reference clocks for the SATA and SGMII interfaces are SD2_REF_CLK and, $\overline{\text{SD2\_REF\_CLK}}$.

The following sections describe the SerDes reference clock requirements and some application information.

2.20.2.1 SerDes Reference Clock Receiver Characteristics

Figure 58 shows a receiver reference diagram of the SerDes reference clocks.

- The supply voltage requirements for $X2V_{DD}$ are specified in Table 2 and Table 3.
- SerDes Reference Clock Receiver Reference Circuit Structure
  — The SDn_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$ are internally AC-coupled differential inputs as shown in Figure 58. Each differential clock input (SD*n*_REF_CLK or $\overline{\text{SD}n\text{\_REF\_CLK}}$) has a 50-Ω termination to SGND (xcorevss) followed by on-chip AC-coupling.

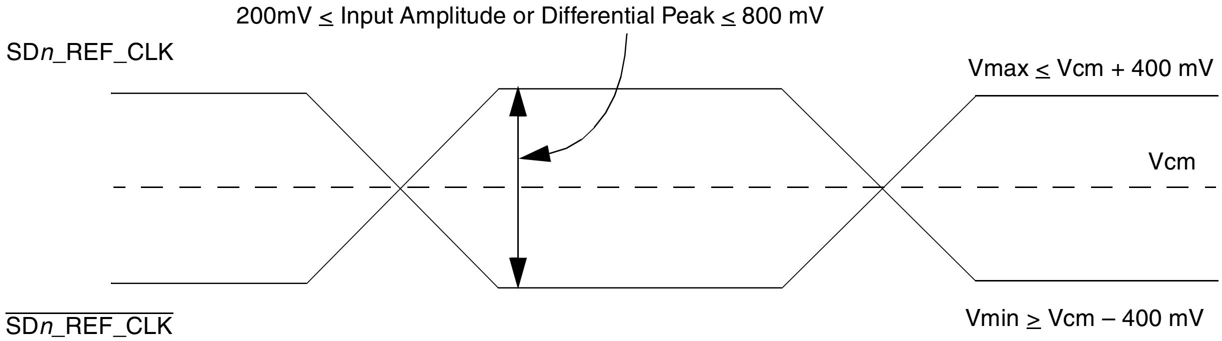

Figure 60. Differential Reference Clock Input DC Requirements (External AC-Coupled)

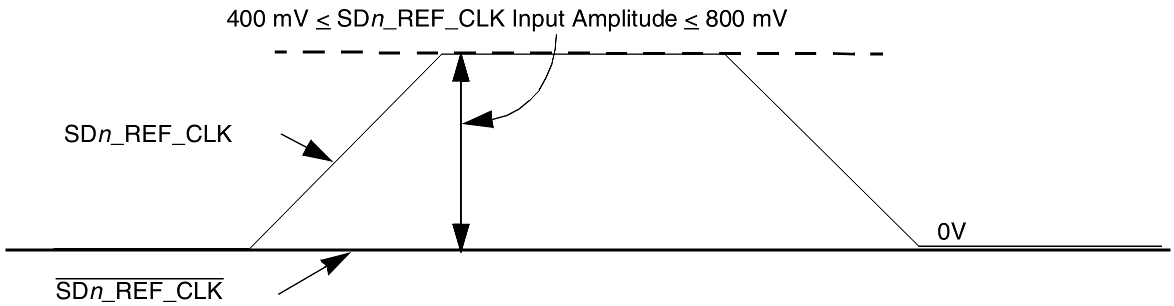

Figure 61. Single-Ended Reference Clock Input DC Requirements

2.20.2.3 Interfacing With Other Differential Signaling Levels

With on-chip termination to SnGND (xcorevss), the differential reference clocks inputs are HCSL (High-Speed Current Steering Logic) compatible DC-coupled.

Many other low voltage differential type outputs like LVDS (Low Voltage Differential Signaling) can be used but may need to be AC-coupled due to the limited common mode input range allowed (100 to 400 mV) for DC-coupled connection.

LVPECL (Low Voltage Positive Emitter-Coupled Logic) outputs can produce signal with too large amplitude and may need to be DC-biased at clock driver output first, then followed with series attenuation resistor to reduce the amplitude, in addition to AC-coupling.

NOTE

Figure 62 to Figure 65 below are for conceptual reference only. Due to the fact that clock driver chip's internal structure, output impedance and termination requirements are different between various clock driver chip manufacturers, it is very possible that the clock circuit reference designs provided by clock driver chip vendor are different from what is shown below. They might also vary from one vendor to the other. Therefore, Freescale Semiconductor can neither provide the optimal clock driver reference circuits, nor guarantee the correctness of the following clock driver connection reference circuits. The system designer is recommended to contact the selected clock driver chip vendor for the optimal reference circuits with the chip’s SerDes reference clock receiver requirement provided in this document.

2.21.4.2 Transmitter Compliance Eye Diagrams

The TX eye diagram in Figure 69 is specified using the passive compliance/test measurement load (see Figure 71) in place of any real PCI Express interconnect + RX component.

There are two eye diagrams that must be met for the transmitter. Both eye diagrams must be aligned in time using the jitter median to locate the center of the eye diagram. The different eye diagrams will differ in voltage depending whether it is a transition bit or a de-emphasized bit. The exact reduced voltage level of the de-emphasized bit will always be relative to the transition bit.

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function (that is, least squares and median deviation fits).

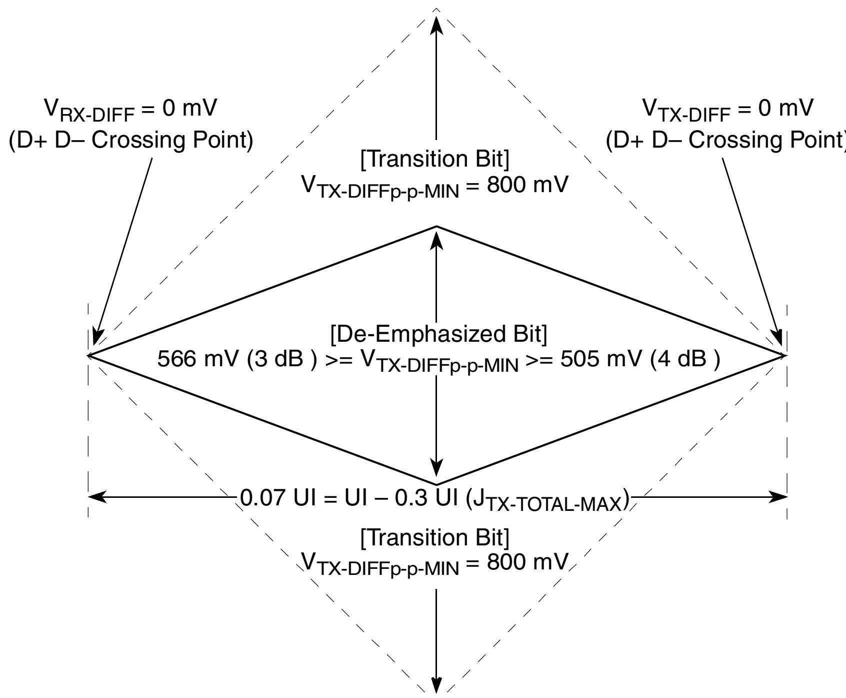

Figure 69. Minimum Transmitter Timing and Voltage Output Compliance Specifications

2.21.4.3 Differential Receiver (RX) Input Specifications

This table defines the specifications for the differential input at all receivers (RXs). The parameters are specified at the component pins.

Table 72. Differential Receiver (RX) Input Specifications

Symbol	Parameter	Min	Nom	Max	Units	Comments
UI	Unit Interval	399.88	400	400.12	ps	Each UI is 400 ps ± 300 ppm. UI does not account for Spread Spectrum Clock dictated variations. See Note 1.
$V_{RX\text{-}DIFFp\text{-}p}$	Differential Peak-to-Peak Output Voltage	0.175	—	1.200	V	$V_{RX\text{-}DIFFp\text{-}p} = 2*\lvert V_{RX\text{-}D+} - V_{RX\text{-}D-}\rvert$ See Note 2.
$T_{RX\text{-}EYE}$	Minimum Receiver Eye Width	0.4	—	—	UI	The maximum interconnect media and Transmitter jitter that can be tolerated by the Receiver can be derived as $T_{RX\text{-}MAX\text{-}JITTER} = 1 - T_{RX\text{-}EYE} = 0.6$ UI. See Notes 2 and 3.
$T_{RX\text{-}EYE\text{-}MEDIAN\text{-}to\text{-}MAX\text{-}JITTER}$	Maximum time between the jitter median and maximum deviation from the median.	—	—	0.3	UI	Jitter is defined as the measurement variation of the crossing points ($V_{RX\text{-}DIFFp\text{-}p} = 0$ V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI. See Notes 2, 3 and 7.
$V_{RX\text{-}CM\text{-}ACp}$	AC Peak Common Mode Input Voltage	—	—	150	mV	$V_{RX\text{-}CM\text{-}ACp} = \lvert V_{RXD+} - V_{RXD-}\rvert/2 + V_{RX\text{-}CM\text{-}DC}$ $V_{RX\text{-}CM\text{-}DC} = DC_{(avg)}$ of $\lvert V_{RX\text{-}D+} + V_{RX\text{-}D-}\rvert/2$ See Note 2
$RL_{RX\text{-}DIFF}$	Differential Return Loss	15	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D- lines biased at +300 mV and –300 mV, respectively. See Note 4
$RL_{RX\text{-}CM}$	Common Mode Return Loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D- lines biased at 0 V. See Note 4
$Z_{RX\text{-}DIFF\text{-}DC}$	DC Differential Input Impedance	80	100	120	Ω	RX DC Differential mode impedance. See Note 5
$Z_{RX\text{-}DC}$	DC Input Impedance	40	50	60	Ω	Required RX D+ as well as D- DC Impedance (50 ± 20% tolerance). See Notes 2 and 5.
$Z_{RX\text{-}HIGH\text{-}IMP\text{-}DC}$	Powered Down DC Input Impedance	200 k	—	—	Ω	Required RX D+ as well as D– DC Impedance when the Receiver terminations do not have power. See Note 6.
$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$	Electrical Idle Detect Threshold	65	—	175	mV	$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p} = 2*\lvert V_{RX\text{-}D+} - V_{RX\text{-}D-}\rvert$ Measured at the package pins of the Receiver
$T_{RX\text{-}IDLE\text{-}DET\text{-}DIFF\text{-}ENTERTIME}$	Unexpected Electrical Idle Enter Detect Threshold Integration Time	—	—	10	ms	An unexpected Electrical Idle ($V_{RX\text{-}DIFFp\text{-}p} < V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$) must be recognized no longer than $T_{RX\text{-}IDLE\text{-}DET\text{-}DIFF\text{-}ENTERING}$ to signal an unexpected idle condition.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

The reference impedance for return loss measurements is 50. to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50. probes—see Figure 71). Note that the series capacitors, CTX, are optional for the return loss measurement.

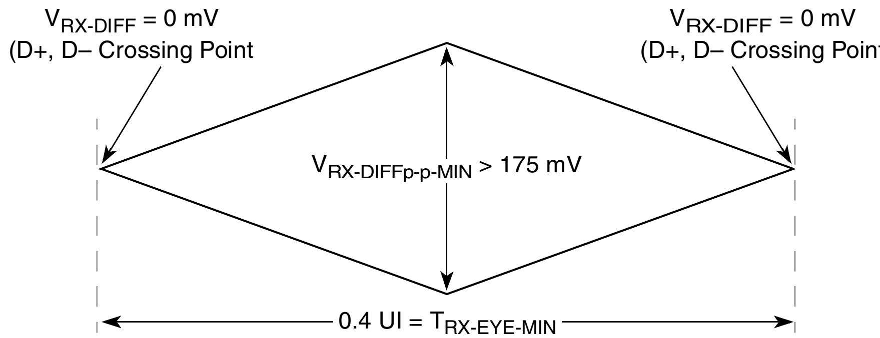

Figure 70. Minimum Receiver Eye Timing and Voltage Compliance Specification

2.22.1 Compliance Test and Measurement Load

The AC timing and voltage parameters must be verified at the measurement point, as specified within 0.2 inches of the package pins, into a test/measurement load shown in the following figure.

NOTE

The allowance of the measurement point to be within 0.2 inches of the package pins is meant to acknowledge that package/board routing may benefit from D+ and D– not being exactly matched in length at the package pin boundary.

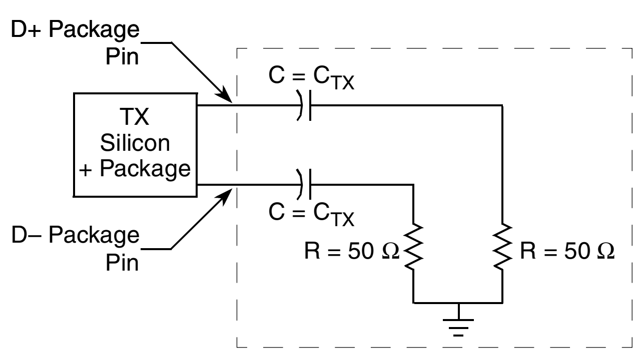

Figure 71. Compliance Test/Measurement Load

2.23 Clocking

This section describes the PLL configuration of the chip. Note that the platform clock is identical to the core complex bus (CCB) clock.

Please note that the DDR PLL reference clock input, DDRCLK, is only required in asynchronous mode.

The DDRCLKDR configuration register in the Global Utilities block allows the DDR controller to be run in a divided down mode where the DDR bus clock is half the speed of the default configuration. Changing of these defaults must be completed prior to initialization of the DDR controller.

Table 77. DDR Clock Ratio

Functional Signals	Reset Configuration Name	Value (Binary)	DDR:DDRCLK Ratio
TSEC_1588_TRIG_OUT[0:1], TSEC1_1588_CLK_OUT	**cfg_ddr_pll[0:2]**	000	3:1
		001	4:1
		010	6:1
		011	8:1
		100	10:1
		101	12:1
		110	Reserved
		111	Synchronous mode

2.23.5 PCI Clocks

The integrated PCI controller in this chip supports PCI input clock frequency in the range of 33–66 MHz. The PCI input clock can be applied from SYSCLK in synchronous mode or PCI1_CLK in asynchronous mode. For specifications on the PCI1_CLK, refer to the PCI 2.2 Specification.

The use of PCI1_CLK is optional if SYSCLK is in the range of 33–66 MHz. If SYSCLK is outside this range then use of PCI1_CLK is required as a separate PCI clock source, asynchronous with respect to SYSCLK.

Table 79. Package Thermal Characteristics (continued)

Characteristic	JEDEC Board	Symbol	Value	Unit	Notes
Junction-to-ambient (@200 ft/min)	Four layer board (2s2p)	$R_{\theta JA}$	14	°C/W	1, 2
Junction-to-board thermal	—	$R_{\theta JB}$	10	°C/W	3
Junction-to-case thermal	—	$R_{\theta JC}$	< 0.1	°C/W	4

Notes
1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 and JESD51-6 with the board (JESD51-9) horizontal.
3. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
4. Thermal resistance between the active surface of the die and the case top surface determined by the cold plate method (MIL SPEC-883 Method 1012.1) with the calculated case temperature. Actual thermal resistance is less than 0.1 •C/W

Simulations with heat sinks were done with the package mounted on the 2s2p thermal test board. The thermal interface material was a typical thermal grease such as Dow Corning 340 or Wakefield 120 grease.For system thermal modeling, the chip's thermal model without a lid is shown in Figure 72 The substrate is modeled as a block 29 x 29 x 1.2 mm with an in-plane conductivity of 19.8 W/m•K and a through-plane conductivity of 1.13 W/m•K. The solder balls and air are modeled as a single block 29 x 29 x 0.5 mm with an in-plane conductivity of 0.034 W/m•K and a through plane conductivity of 12.1 W/m•K. The die is modeled as 9.6 x 9.57 mm with a thickness of 0.75 mm. The bump/underfill layer is modeled as a collapsed thermal resistance between the die and substrate assuming a conductivity of 7.5 W/m•K in the thickness dimension of 0.07 mm. The die is centered on the substrate. The thermal model uses approximate dimensions to reduce grid. Please refer to the case outline for actual dimensions.

2.24.2 Recommended Thermal Model

This table shows the chip's thermal model.

Table 80. Thermal Model

Conductivity	Value	Units
Die (9.6x9.6 × 0.85 mm)		
Silicon	Temperature dependent	—
Bump/Underfill (9.6 x 9.6 × 0.07 mm) Collapsed Thermal Resistance		
Kz	7.5	W/m•K
Substrate (29 × 29 × 1.2 mm)		
Kx	19.8	W/m•K
Ky	19.8	
Kz	1.13	
Solder and Air (29 × 29 × 0.5 mm)		
Kx	0.034	W/m•K
Ky	0.034	
Kz	12.1	

4.1 Part Numbers Fully Addressed by this Document

This table shows the part numbering nomenclature.

Table 82. Part Numbering Nomenclature

MPC	*nnnn*	*E*	*C*	*VT*	*AA*	*X*	*R*
Product Code	**Part Identifier**	**Security Engine**	**Tiers and Temperature Range**	**Package [1]**	**Processor Frequency [2]**	**DDR Frequency[3]**	**Revision Level**
MPC	8536 8535	E = included	• A = Commercial tier standard temperature range (0° to 90°C) • B or Blank = industrial tier standard temperature range (0° to 105°C) • C = Industrial tier extended temperature range (–40° to 105°C)	• VT = FC-PBGA • (Pb-free) • PX = plastic standard	• AK = 600 MHz • AN = 800 MHz • AQ = 1000 MHz • AT = 1250 MHz • AU = 1333 MHz • AV = 1500 MHz	• G = 400 MHz • H = 500 MHz • J = 533 MHz • L = 667 MHz	• Blank = Ver. 1.0 or 1.1 (SVR = 0x803F0190, 0x803F0191) • A = Ver. 1.2 (SVR = 0x803F0192)
		Blank = not included					• Blank = Ver. 1.0 or 1.1 (SVR = 0x80370190, 0x80370191) • A = Ver. 1.2 (SVR = 0x80370192)

Notes:

1. See Section 5, "Package Information," for more information on available package types.
2. Processor core frequencies supported by parts addressed by this specification only. Not all parts described in this specification support all core frequencies. Additionally, parts addressed by part number specifications may support other maximum core frequencies.
3. See Table 84 for the corresponding maximum platform frequency.